

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10526520	SCHULIST ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Nguyen, Hai V	2618	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	335	12/22/2007	HN

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	12/21/2007; 01/03/2008	HN
EAST search updated	05/29/2008	HN
EAST search updated (see search history printout report)	01/10/2009	HN
EAST search updated (see search history printout report)	10/14/2009	HN

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>